10/593792 Attorney's Docket No.: 12406-213US1/P2004,0273 US N IAP9/Rec'd PCT/PTO 21 SEP 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Arndt Jaeger et al.

Art Unit : Unknown

Serial No.: To Be Assigned

Examiner: Unknown

Filed

: Herewith

Title

: RADIATION DETECTOR

## **Mail Stop PCT**

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## INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request. A copy of a communication from a foreign patent office in a PCT application Serial No. PCT/DE2005/000428 is also enclosed.

This statement is being filed with the application. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

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Sheet <u>1</u> of <u>2</u>

Substitute Form PTO-1449 (Modified)

IAPOIREC' DE POTO 21 SEP 2003 U.S. Department of Commerce Patent and Trademark Office

Attorney's Docket No. 12406-213US1

Application No. To Be Assigned

**Information Disclosure Statement** 

**Applicant** 

by Applicant (Use several sheets if necessary)

Arndt Jaeger et al.

Filing Date Herewith **Group Art Unit** 

(37 CFR §1.98(b))

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	3,508,126	04/21/1970	Newman, P.C et al.			
	AB	3,903,413	09/02/1975	Manning			
	AC	4,451,691	05/29/1984	Fraas			
	AD	4,713,493	12/05/1987	Ovshinsky			
	AE	4,820,915	04/11/1989	Hamakawa et al.			
	AF	5,406,067	04/11/1995	Keller			
	AG	5,583,351	12/10/1996	Brown et al.			
	AH	5,600,157	02/04/1997	Abiko et al.			
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	AJ	2003/0001167	01/02/2003	Eriksson et al.			
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translatio	- <del></del>
Initial	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
	AL	DE 626680	02/29/1936	Germany			Abstract	
	AM	DE 2315054	10/03/1974	Germany			Abstract	
	AN	DT 2457572	06/12/1975	Germany			Equivalent to US 3,903,413	
	AO	DE 19621965	12/04/1997	Germany			Abstract	
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	AQ	EP 0 509215	10/21/1992	Europe				
	AR	GB 2 107112	04/20/1983	Great Britain				
	AS	JP 2001308351	11/02/2001	Japan			Abstract	
	AT	JР 2003150089	05/21/2003	Japan			Abstract	
	AU	TW473893	01/21/2002	Taiwan			Abstract	allivorethe Photometrothe
•	AV	WO 98/22982	05/28/1998	WIPO			Abstract	
	AW	WO 2005/041247	05/06/2005	WIPO			Abstract	

Examiner Signature	Date Considered '
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10/593792

artment of Commerce Attorney's Docket No. Apr Sheet <u>2</u> of <u>2</u>

U.S. Department of Commerce Application No. Substitute Form PTO-1449 Patent and Trademark Office To Be Assigned 12406-213US1 (Modified) **Applicant Information Disclosure Statement** 

Arndt Jaeger et al.

by Applicant (Use several sheets if necessary) Filing Date **Group Art Unit** Herewith

(37 CFR §1.98(b))

	Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner Initial	Desig. ID	Document				
	AX	Karrer, U. et al., "AIGaN-based Ultraviolet Light Detectors with Integrated Optical Filters", Journal of Vacuum Science & Technology B, Vol. 18, No. 2, pp. 757-760, 2000.				
	AY	Authorized officer: Werner, A, International Search Report, PCT/DE2005/000428, 2005.				
	AZ					
	AAA					

Examiner Signature	Date Considered

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